

**AMENDMENTS TO THE CLAIMS**

1. – 11. (Canceled)

12. (Currently Amended) A method for conducting a cooking process in a cooking chamber of a cooking appliance using a cooking process probe which is to be inserted at least partly into an item being cooked in the cooking chamber for detecting at least one variable of the item being cooked, comprising the steps of:

at least at one predetermined point in time, automatically monitoring to detect non-insertion of the cooking process probe in which at least one of the following steps is performed:

at least one of a conductivity value, a resistance value, an induction value, a capacitance, a pressure characteristic, and a characteristic of at least one of an electric, magnetic, or electromagnetic field is detected over a period of time or by forming time derivatives for monitoring whether the cooking process probe is in a standby position in a retaining device provided by the cooking appliance or in a measuring position in a positioning device provided by an accessory part for receiving the item being cooked,

at least one of a conductivity value, a resistance value, an induction value, a capacitance value, a potential difference value, a weight value, a moisture value, a radiation characteristic, a pressure characteristic, and a characteristic of at least one of an electric, magnetic, or electromagnetic field is detected over a period of time or by forming time derivatives for monitoring whether the cooking process probe is removed from the retaining device or the positioning device,

at least one of radiation characteristics and a characteristic of at least one of an electric, magnetic, or electromagnetic field is detected over a period of time or by forming time derivatives for monitoring whether the cooking process probe is at least one of moved or positioned inside the cooking appliance, and

at least one of a conductivity value, a resistance value, an induction value, a capacitance value, a potential difference value, a moisture value, a radiation characteristic, a pressure characteristic and a characteristic of at least one of an electric, magnetic, or electromagnetic field is detected over a period of time or by